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| Notice of References Cited | | Application/Control No. 10/604,794 | Applicant(s)/Patent Under Reexamination CHEN ET AL | |
| | | Examiner Alexander O Williams | Art Unit 2826 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|---------------------|----------------|
| | A | US-2003/0116845 A1 | 06-2003 | Bojkov et al. | 257/738 |
| | B | US-2003/0189261 A1 | 10-2003 | Tong et al. | 257/780 |
| | C | US-2003/0080392 A1 | 05-2003 | Zuniga-Ortiz et al. | 257/503 |
| | D | US-2003/0162380 A1 | 08-2003 | TONG et al. | 438/613 |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
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NON-PATENT DOCUMENTS

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|---|---|---|
| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
| | U | |
| | V | |
| | W | |
| | X | |

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